

Day 1 May 15th, 2017

Start	Session	Duration
13:00	Registration and Coffee & Snacks Service <ul style="list-style-type: none"> Distribution of badges, presentation papers etc. 	60min
14:00	Opening Remarks to ITWS 9 Organisational items Speaker: Torsten Liese & David Liese	30min
14:30	1 st Session: AFORE, Lieto (Finland) “Probers With Physical Stimulus – Introduction To Technology And Benefits On WLP MEMS Sensor Final Test.” Speaker: Ari Kuukkala <ul style="list-style-type: none"> Q & A related to this session 	45min
15:15	2 nd Session: T.I.P.S. Messtechnik GmbH, Villach (Austria) “Challenges For Wafer Sort Of High- Power Devices” Speaker: Georg Franz <ul style="list-style-type: none"> Q & A related to this session 	45min
16:00	Coffee Break	45min
16:45	3 rd Session: JEM Europe, Montbonnot (France) “Habits For Highly Effective Probing” Speaker: Joe Mai <ul style="list-style-type: none"> Q & A related to this session 	45min
17:30	4 th Session - FEINMETALL GmbH, Herrenberg (Germany) “Thermal Characterization Of A Probe Card And How To Enhance A Probe Card Setup Process Using Fiducials” Speaker: Helmut Seefeldt <ul style="list-style-type: none"> Q & A related to this session 	45min
18:30	Dinner	

Day 2 May 16th, 2017

Start	Session	Duration
09:15	5 th Session: Turbodynamics, Stephanskirchen (Germany) “A Modular Head Plate Concept For A Combined Test Head Docking” Speaker: Stefan Thurmaier <ul style="list-style-type: none"> Q & A related to this session 	45min
10:00	6 th Session: HTT Group, Munich (Germany) “Single Wafer Tracking @ Wafer Probing” Speaker: Michael Köppl <ul style="list-style-type: none"> Q & A related to this session 	45min
10:45	Coffee Break	30min
11:15	7 th Session: aSpect Systems GmbH, Dresden (Germany) “PCI Express Extension Into Your Test Head / How To Capture High Bandwidth And Big Data Volume” Speaker: Marcus Verhoeven <ul style="list-style-type: none"> Q & A related to this session 	45min
12:00	8 th Session: FEINMETALL GmbH, Herrenberg (Germany) “A Singular Package Testing Using A Vertical Probe Card And Manual Actuator” Speaker: Krzysztof Dabrowiecki <ul style="list-style-type: none"> Q & A related to this session 	45min
12:45	Summary of 9 th ITWS Speaker: Torsten Liese	15min
13:00	End of Workshop	

Please see www.is-test.com and follow the link [Workshop (ITWS)] for updated documents.